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Title: **JP9002565A2: RECEIVING TRAY FOR SEMICONDUCTOR DEVICE AND METHOD INSPECTING APPEARANCE OF BENT LEAD OF SEMICONDUCTOR DEVICE**

Country: **JP Japan**

Kind: **A2 Document Laid open to Public inspection**

Inventor: **HIROSE HAYAMI;**

Assignee: **NEC CORP**
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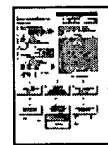
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